# International Rectifier

## IRLML2803

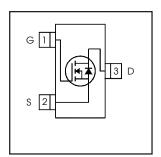
HEXFET® Power MOSFET

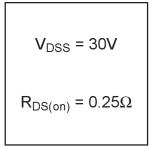
- Generation V Technology
- Ultra Low On-Resistance
- N-Channel MOSFET
- SOT-23 Footprint
- Low Profile (<1.1mm)
- Available in Tape and Reel
- Fast Switching



Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

A customized leadframe has been incorporated into the standard SOT-23 package to produce a HEXFET Power MOSFET with the industry's smallest footprint. This package, dubbed the Micro3, is ideal for applications where printed circuit board space is at a premium. The low profile (<1.1mm) of the Micro3 allows it to fit easily into extremely thin application environments such as portable electronics and PCMCIA cards.







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units			
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	1.2				
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	0.93	Α			
I <sub>DM</sub>	Pulsed Drain Current ①	7.3				
$P_D @ T_A = 25^{\circ}C$	Power Dissipation	540	mW			
	Linear Derating Factor	4.3	mW/°C			
$V_{GS}$	Gate-to-Source Voltage	±20	V			
E <sub>AS</sub>	Single Pulse Avalanche Energy®	3.9	mJ			
dv/dt	Peak diode Recovery dv/dt <sup>②</sup>	5.0	V/ns			
T <sub>J</sub> ,T <sub>STG</sub> Junction and Storage Temperature Range		-55 to + 150	°C			

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ®		230	°C/W

## IRLML2803

International **IOR** Rectifier

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.029		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Б	Static Drain to Source On Registence			0.25		V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.91A ③
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.40	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.46A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
<b>9</b> fs	Forward Transconductance	0.87			S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.46A
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
יטכט	Brain to obtaine Educage Garrent			25	μΑ	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			-100	nA	$V_{GS} = -20V$
1655	Gate-to-Source Reverse Leakage			100	ПА	V <sub>GS</sub> = 20V
Qg	Total Gate Charge		3.3	5.0		$I_D = 0.91A$
Q <sub>gs</sub>	Gate-to-Source Charge		0.48	0.72	nC	V <sub>DS</sub> = 24V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		1.1	1.7		V <sub>GS</sub> = 10V, See Fig. 6 and 9 ③
t <sub>d(on)</sub>	Turn-On Delay Time		3.9			V <sub>DD</sub> = 15V
t <sub>r</sub>	Rise Time		4.0		ns	$I_D = 0.91A$
t <sub>d(off)</sub>	Turn-Off Delay Time		9.0		115	$R_G = 6.2\Omega$
t <sub>f</sub>	Fall Time		1.7			$R_D$ = 16 $\Omega$ , See Fig. 10 ③
C <sub>iss</sub>	Input Capacitance		85			V <sub>GS</sub> = 0V
Coss	Output Capacitance		34		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		15			f = 1.0MHz, See Fig. 5

## **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			0.54		MOSFET symbol
	(Body Diode)			0.54	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			7.0		integral reverse
	(Body Diode) ①			7.3		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25$ °C, $I_S = 0.91$ A, $V_{GS} = 0$ V ③
t <sub>rr</sub>	Reverse Recovery Time		26	40	ns	$T_J = 25^{\circ}C, I_F = 0.91A$
Q <sub>rr</sub>	Reverse RecoveryCharge		22	32	nC	di/dt = 100A/µs ③

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} @ I_{SD} \le 0.91A, & di/dt \le 120A/\mu s, & V_{DD} \le V_{(BR)DSS}, \\ & T_J \le 150 ^{\circ}C \end{tabular}$

- $\ \ \,$  Limited by  $\rm T_{Jmax}, \ starting \ T_{J}$  = 25°C, L = 9.4mH,  $\rm R_{G}$  = 25 $\Omega, \ I_{AS}$  = 0.9A.

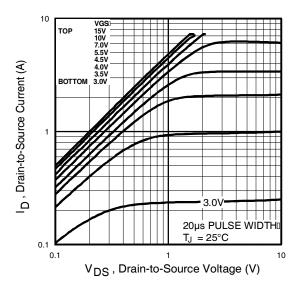


Fig 1. Typical Output Characteristics

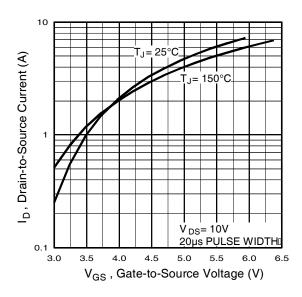


Fig 3. Typical Transfer Characteristics

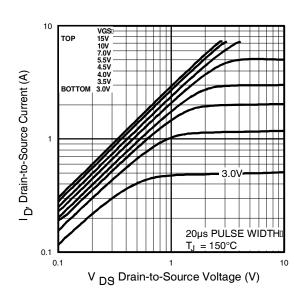
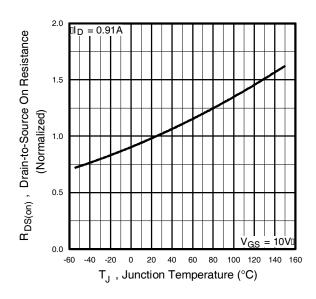
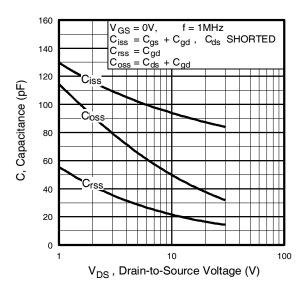


Fig 2. Typical Output Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

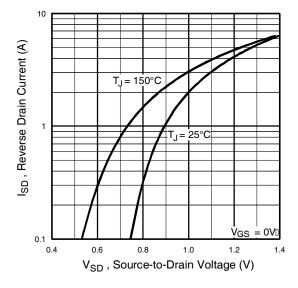
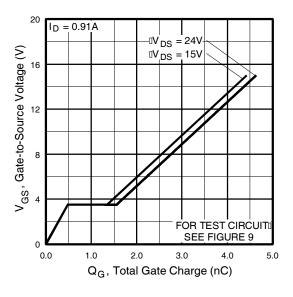


Fig 7. Typical Source-Drain Diode Forward Voltage www.irf.com



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

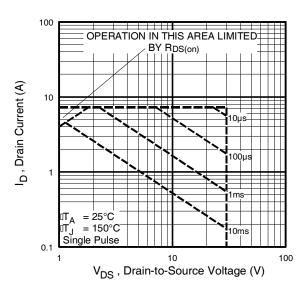


Fig 8. Maximum Safe Operating Area

4

International

TOR Rectifier

## IRLML2803

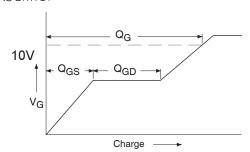


Fig 9a. Basic Gate Charge Waveform

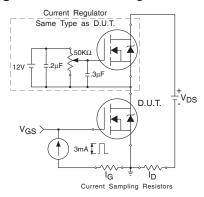


Fig 9b. Gate Charge Test Circuit

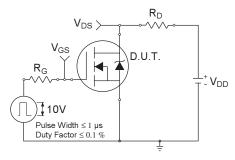


Fig 10a. Switching Time Test Circuit

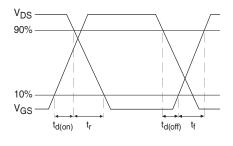


Fig 10b. Switching Time Waveforms

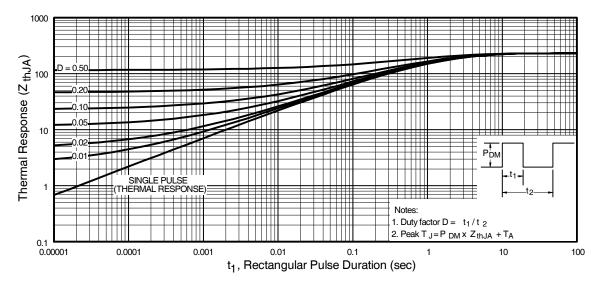


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

IRLML2803 International TOR Rectifier

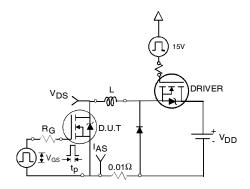


Fig 12a. Unclamped Inductive Test Circuit

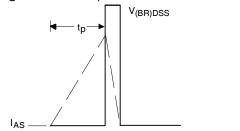
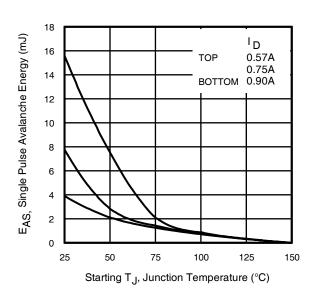


Fig 12b. Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

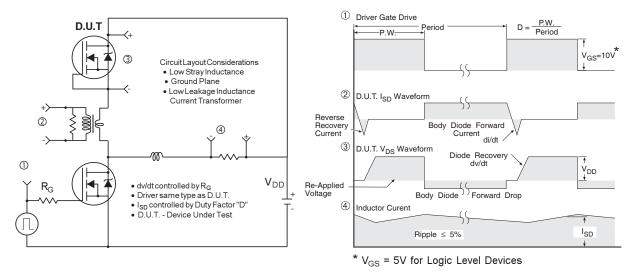


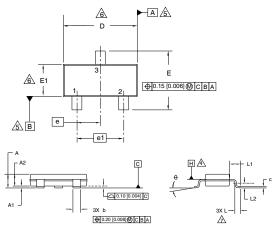
Fig 13. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

International IOR Rectifier

## IRLML2803

### Micro3 (SOT-23) (Lead-Free) Package Outline

Dimensions are shown in millimeters (inches)



DIMENSIONS						
SYMBOL	MILLIM	ETERS	INCHES			
	MIN	MAX	MIN	MAX		
Α	0.89	1.12	0.035	0.044		
A1	0.01	0.10	0.0004	0.004		
A2	0.88	1.02	0.035	0.040		
b	0.30	0.50	0.012	0.020		
С	0.08	0.20	0.003	0.008		
D	2.80	3.04	0.110	0.120		
Е	2.10	2.64	0.083	0.104		
E1	1.20	1.40	0.047	0.055		
е	0.95	BSC	0.037	BSC		
e1	1.90	BSC	0.075	BSC		
L	0.40	0.60	0.016	0.024		
L1	0.54	REF	0.021	REF		
L2	0.25	BSC	0.010	BSC		
0	0	8	0	8		

## Recommended Footprint 2.742

#### NOTES:

- 1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1994
  2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
  3. CONTROLLING DIMENSION: MILLIMETERS [INCHES].

  \$\(\frac{1}{2}\) DATIME HALBER HIS LOCATED AT THE MOLD PARTING LINE.

  \$\(\frac{1}{2}\) DATIME AND B TO BE DETERMINED AT DATUM PLANE H.

  \$\(\frac{1}{2}\) DATIME AND B TO BE DETERMINED AT DATUM PLANE H.

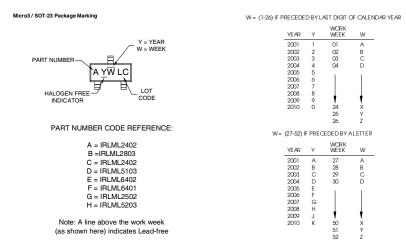
  \$\(\frac{1}{2}\) DIMENSIONS D AND E I ARE MEASURED AT DATUM PLANE H. DIMENSIONS DOES

  NOT INCLUDE MOLD PROTRUSIONS OR INTERLEAD FLASH. MOLD PROTRUSIONS
  OR INTERLEAD FLASH SHALL NOT EXCEED 0.25 MM [0.010 INCH] PER SIDE.

  \$\(\frac{1}{2}\) DIMENSION L IS THE LEAD LENGTH FOR SOLDERING TO A SUBSTRATE.

  8. OUTLINE CONFORMS TO JEDEC OUTLINE TO 236 AB.

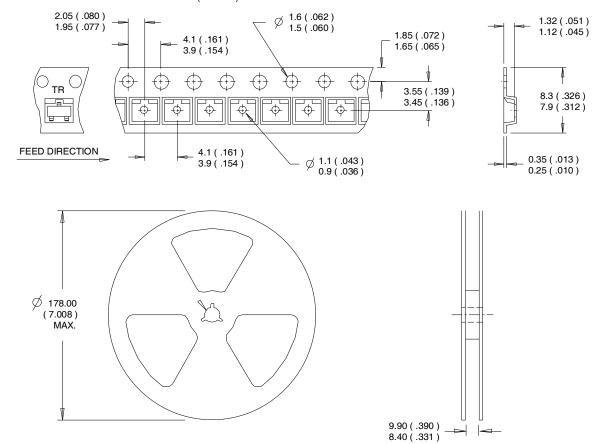
## Micro3 (SOT-23 / TO-236AB) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package

## Tape & Reel Information

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package

Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 101N.Sepulveda Blvd, El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 12/2011 www.irf.com